

<b>Notice of References Cited</b>	Application/Control No. 10/064,252	Applicant(s)/Patent Under Reexamination YEH, CHIEN-LIANG	
	Examiner Cheukfan Lee	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,687,024	02-2004	Short et al.	358/474
*	B	US-5,652,665	07-1997	Chen et al.	358/487
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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